| Reexamination  |
|----------------|
| OKUMURA ET AL. |
| Art Unit       |
| 2611           |
|                |
|                |

| SEARCHED |                              |          |          |  |  |  |
|----------|------------------------------|----------|----------|--|--|--|
| Class    | Subclass                     | Date     | Examiner |  |  |  |
| 375      | 147, 148, 260, 224, 316, 324 | 11/19/10 | QG       |  |  |  |
|          |                              | 11/19/10 |          |  |  |  |

| SEARCH NOTES            |             |          |  |  |  |
|-------------------------|-------------|----------|--|--|--|
| Search Notes            | Date        | Examiner |  |  |  |
| Search East, Txt search | 11/16/10    | QG       |  |  |  |
| Inv. search             | 11/16/10    | QG       |  |  |  |
| IEEE X'Plore            | 11/16/10    | QG       |  |  |  |
| Consult SPE, CF         | 11/24/09    | QG       |  |  |  |
| Consult Spe             | 5/25/2010   | QG       |  |  |  |
| Consult spe             | 11/16,11/30 | QG       |  |  |  |

| INTERFERENCE SEARCH |           |          |          |          |  |  |
|---------------------|-----------|----------|----------|----------|--|--|
| Class               |           | Subclass | Date     | Examiner |  |  |
| 375                 | All above |          | 11/16/10 | QG       |  |  |

| /Q. G./<br>Examiner.Art Unit 2611 |  |
|-----------------------------------|--|
|                                   |  |

U.S. Patent and Trademark Office Part of Paper No.: 20101121